

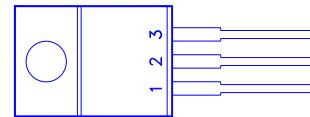
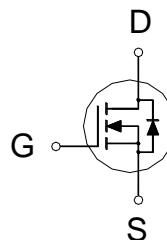
NIKO-SEM**N-Channel Logic Level Enhancement
Mode Field Effect Transistor****P0306BT**

TO-220

Halogen-Free & Lead-Free

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
60V	3.4mΩ	162A


 1.GATE
2.DRAIN
3.SOURCE
ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current ^{2,3}	$T_C = 25^\circ\text{C}$	I_D	162	A
	$T_C = 100^\circ\text{C}$		102	
Pulsed Drain Current ^{1,2}		I_{DM}	300	
Avalanche Current		I_{AS}	119	
Avalanche Energy	$L = 0.1\text{mH}$	E_{AS}	708	mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	178	W
	$T_C = 100^\circ\text{C}$		71	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		0.7	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	°C / W

¹Pulse width limited by maximum junction temperature.²Limited only by maximum temperature allowed.³Package limitation current is 110A.**ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	60			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.3	1.8	2.3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 48\text{V}, V_{GS} = 0\text{V}$			1	μA
		$V_{DS} = 40\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$			10	

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Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 4.5V, I_D = 20A$	3	4.5	$m\Omega$
		$V_{GS} = 10V, I_D = 20A$	2.6	3.4	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 10V, I_D = 20A$	80		S
DYNAMIC					
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$	5825		pF
Output Capacitance	C_{oss}		1162		
Reverse Transfer Capacitance	C_{rss}		385		
Gate Resistance	R_g		1.4		
Total Gate Charge ²	$Q_{g(VGS=10V)}$	$V_{DS} = 30V, V_{GS} = 10V, I_D = 20A$	124		nC
	$Q_{g(VGS=4.5V)}$		67		
Gate-Source Charge ²	Q_{gs}		15		
Gate-Drain Charge ²	Q_{gd}		35		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DD} = 60V$ $I_D \cong 20A, V_{GS} = 10V, R_{GEN} = 6\Omega$	25		ns
Rise Time ²	t_r		65		
Turn-Off Delay Time ²	$t_{d(off)}$		60		
Fall Time ²	t_f		62		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)					
Continuous Current ³	I_S			172	A
Forward Voltage ¹	V_{SD}	$I_F = 20A, V_{GS} = 0V$		1.3	V
Reverse Recovery Time	t_{rr}	$I_F = 20A, dI_F/dt = 100A / \mu S$	60		ns
Reverse Recovery Charge	Q_{rr}		127		nC

¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.³Package limitation current is 110A.

NIKO-SEM

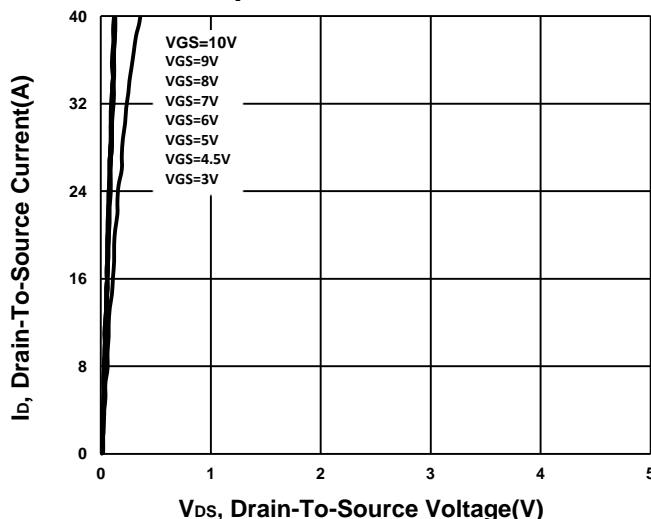
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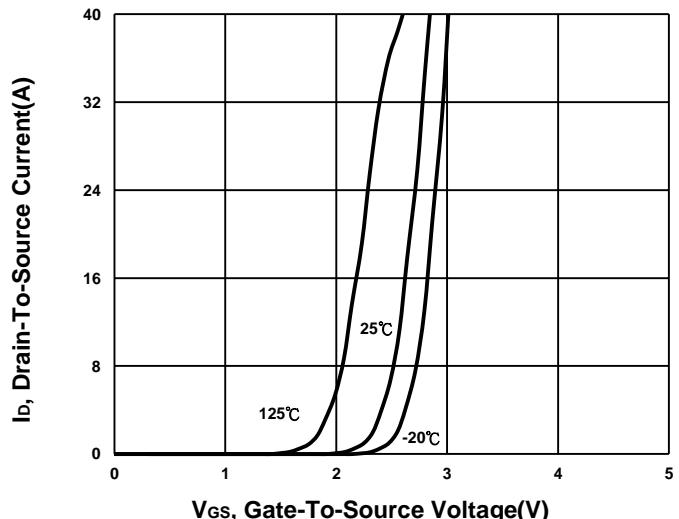
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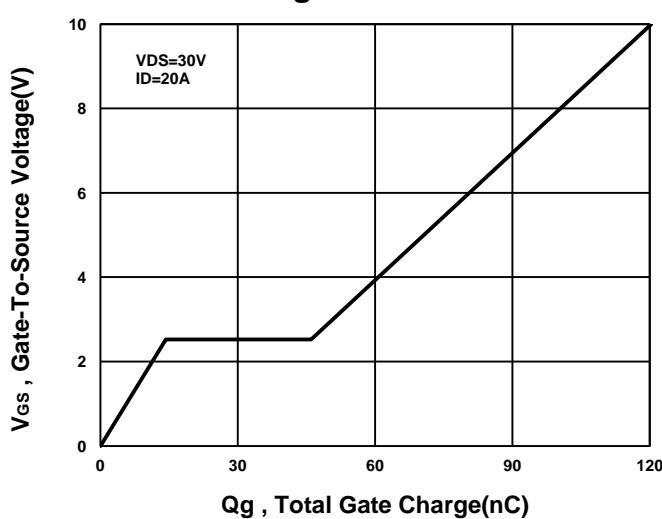
Output Characteristics



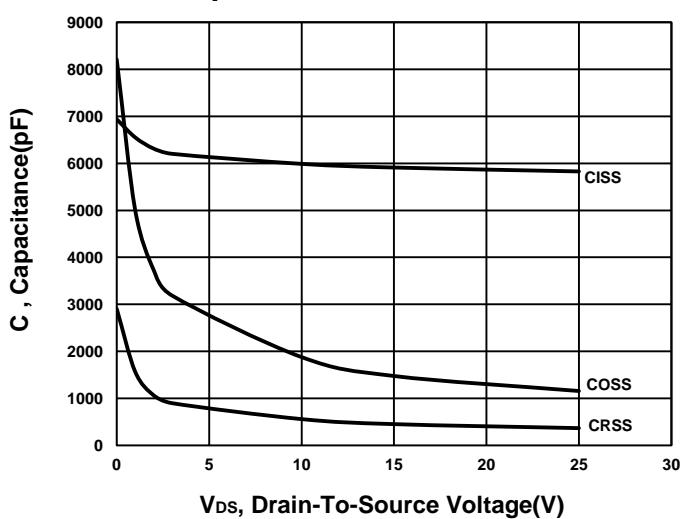
Transfer Characteristics



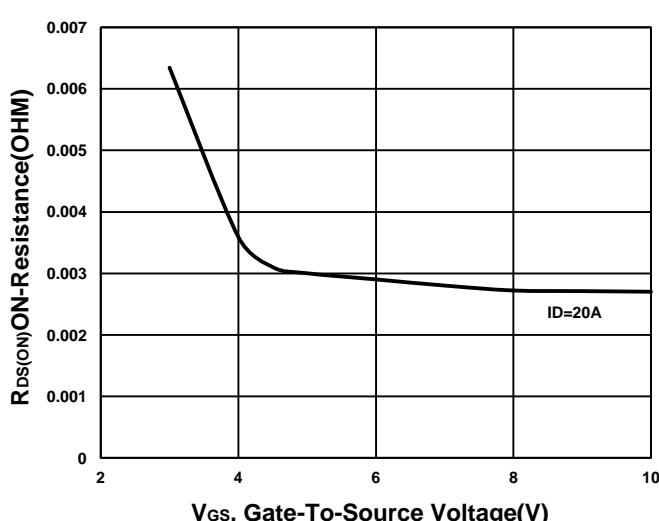
Gate charge Characteristics



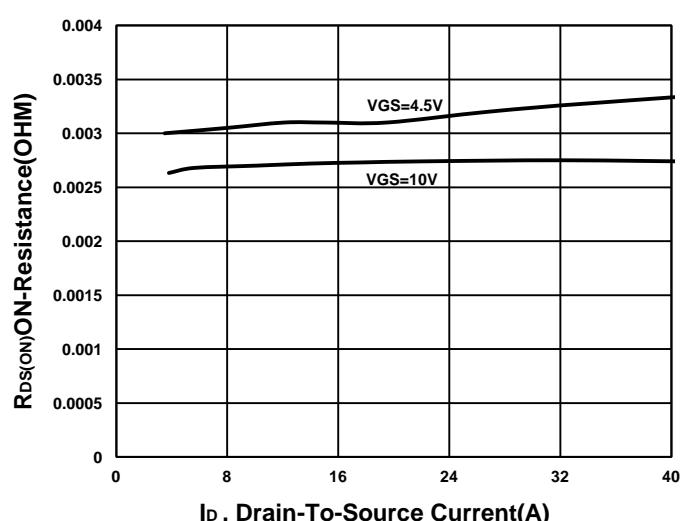
Capacitance Characteristic



On-Resistance VS Gate-To-Source



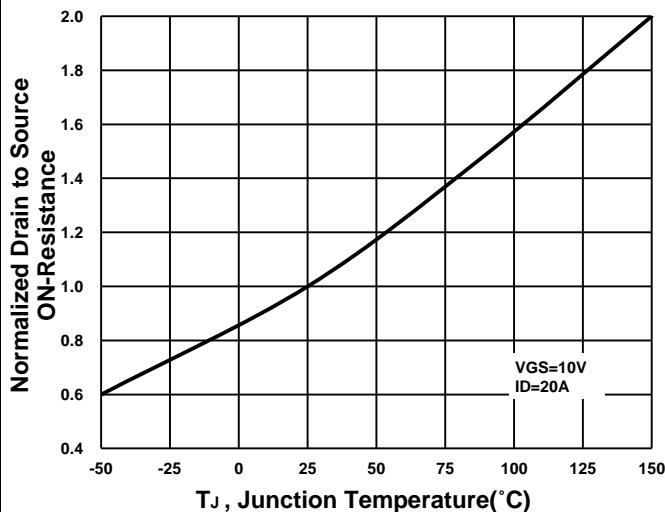
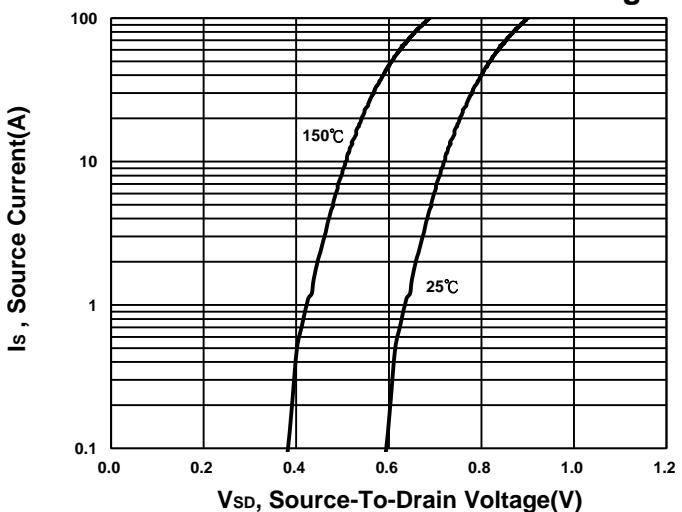
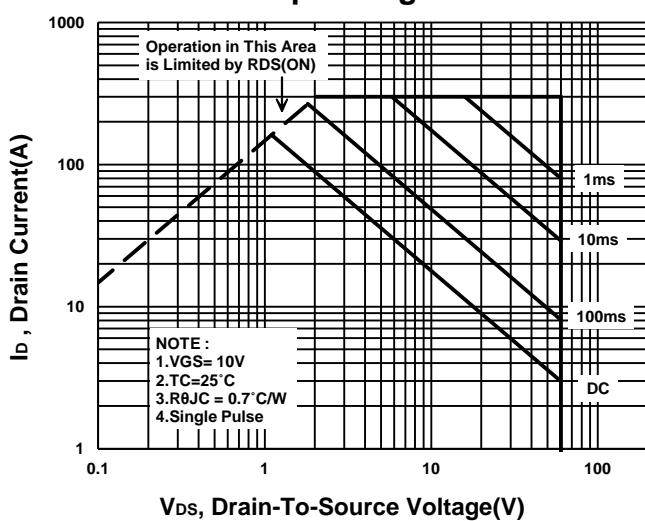
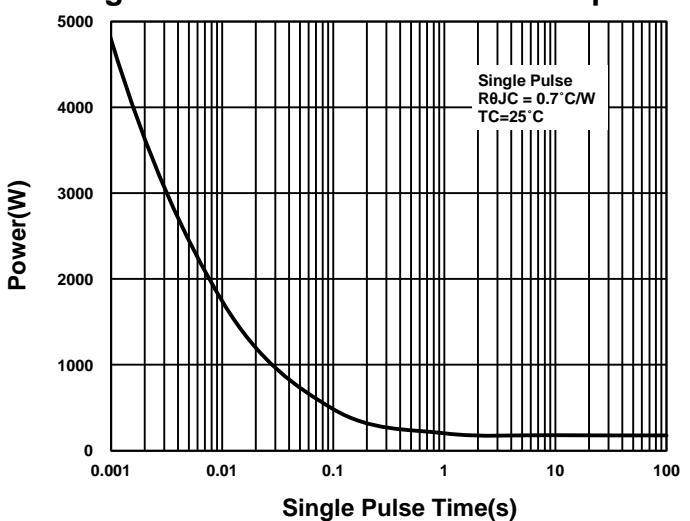
On-Resistance VS Drain Current



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On-Resistance VS Temperature**Source-Drain Diode Forward Voltage****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**